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PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of:

KARSTEN WIECZOREK
ROLF GEILENKEUSER
JÖRG-OLIVER WEIDNER

Serial No.: 10/649,051

Filed: August 27, 2003

For: INTEGRATED SEMICONDUCTOR
STRUCTURE FOR RELIABILITY
TESTS OF DIELECTRICS

Examiner: Andre C. Stevenson

Group Art Unit: 2812

Att'y Docket: 2000.108400/DE0349

Customer No.: 23720

RESPONSE TO FINAL OFFICE ACTION DATED JULY 13, 2005

Mail Stop AF
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

CERTIFICATE OF MAILING
37 C.F.R 1.8

I hereby certify that this correspondence is being deposited with the U.S. Postal Service with sufficient postage as First Class Mail in an envelope addressed to: Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450, on the date below:

September 7, 2005

Date


Signature

This paper is submitted in response to the Final Office Action dated July 13, 2005, for which the three-month date for response is October 13, 2005.

No fees are believed to be due in connection with the present paper. However, should any fees be required under 37 C.F.R. §§ 1.16 to 1.21, the Director is authorized to deduct such fees from Advanced Micro Devices, Inc. Deposit Account No. 01-0365/DE0349. In the event the monies in that account are insufficient, the Director is authorized to withdraw funds from Williams, Morgan & Amerson, P.C. Deposit Account No. 50-0786/2000.108400.

Reconsideration of the application in view of the following amendments and remarks is respectfully requested.